NXP USA Inc. - MPC8358EVRAGDDA Datasheet





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Applications of **Embedded - Microprocessors**

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Active
Core Processor	PowerPC e300
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	400MHz
Co-Processors/DSP	Communications; QUICC Engine, Security; SEC
RAM Controllers	DDR, DDR2
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (1)
SATA	-
USB	USB 1.x (1)
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	Cryptography, Random Number Generator
Package / Case	668-BBGA Exposed Pad
Supplier Device Package	668-PBGA-PGE (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc8358evragdda

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1 Overview

This section describes a high-level overview including features and general operation of the MPC8358E PowerQUICC II Pro processor. A major component of this device is the e300 core, which includes 32 Kbytes of instruction and data cache and is fully compatible with the Power Architecture[™] 603e instruction set. The new QUICC Engine module provides termination, interworking, and switching between a wide range of protocols including ATM, Ethernet, HDLC, and POS. The QUICC Engine module's enhanced interworking eases the transition and reduces investment costs from ATM to IP based systems. The MPC8358E has a single DDR SDRAM memory controller. The MPC8358E also offers a 32-bit PCI controller, a flexible local bus, and a dedicated security engine.

Figure 1 shows the MPC8358E block diagram.

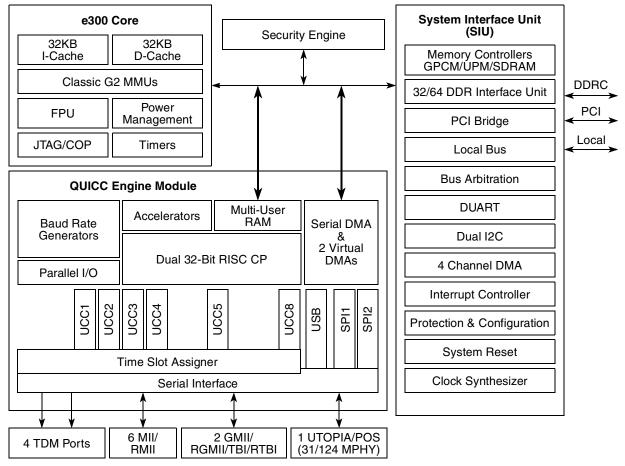


Figure 1. MPC8358E Block Diagram

Major features of the MPC8358E are as follows:

- e300 PowerPC processor core (enhanced version of the MPC603e core)
 - Operates at up to 400 MHz (for the MPC8358E)
 - High-performance, superscalar processor core
 - Floating-point, integer, load/store, system register, and branch processing units



Overview

- ATM (AAL2/AAL5) to Ethernet (IP) interworking in accordance with RFC2684 including bridging of ATM ports to Ethernet ports
- Extensive support for ATM statistics and Ethernet RMON/MIB statistics
- AAL2 protocol rate up to 4 CPS at OC-3/STM-1 rate
- Packet over Sonet (POS) up to 622-Mbps full-duplex 124 MultiPHY
- POS hardware; microcode must be loaded as an IRAM package
- Transparent up to 70-Mbps full-duplex
- HDLC up to 70-Mbps full-duplex
- HDLC BUS up to 10 Mbps
- Asynchronous HDLC
- UART
- BISYNC up to 2 Mbps
- User-programmable Virtual FIFO size
- QUICC multichannel controller (QMC) for 64 TDM channels
- One UTOPIA/POS interface on the MPC8358E supporting 31/124 MultiPHY
- Two serial peripheral interfaces (SPI); SPI2 is dedicated to Ethernet PHY management
- Four TDM interfaces on the MPC8358E with 1-bit mode for E3/T3 rates in clear channel
- Sixteen independent baud rate generators and 30 input clock pins for supplying clocks to UCC serial channels
- Four independent 16-bit timers that can be interconnected as four 32-bit timers
- Interworking functionality:
 - Layer 2 10/100-Base T Ethernet switch
 - ATM-to-ATM switching (AAL0, 2, 5)
 - Ethernet-to-ATM switching with L3/L4 support
 - PPP interworking
- Security engine is optimized to handle all the algorithms associated with IPSec, SSL/TLS, SRTP, 802.11i®, iSCSI, and IKE processing. The security engine contains four crypto-channels, a controller, and a set of crypto execution units (EUs).
 - Public key execution unit (PKEU) supporting the following:
 - RSA and Diffie-Hellman
 - Programmable field size up to 2048 bits
 - Elliptic curve cryptography
 - F2m and F(p) modes
 - Programmable field size up to 511 bits
 - Data encryption standard execution unit (DEU)
 - DES, 3DES
 - Two key (K1, K2) or three key (K1, K2, K3)
 - ECB and CBC modes for both DES and 3DES



- Data bus widths:
 - Single 32-bit data PCI interface that operates at up to 66 MHz
- PCI 3.3-V compatible (not 5-V compatible)
- PCI host bridge capabilities on both interfaces
- PCI agent mode supported on PCI interface
- Support for PCI-to-memory and memory-to-PCI streaming
- Memory prefetching of PCI read accesses and support for delayed read transactions
- Support for posting of processor-to-PCI and PCI-to-memory writes
- On-chip arbitration, supporting five masters on PCI
- Support for accesses to all PCI address spaces
- Parity support
- Selectable hardware-enforced coherency
- Address translation units for address mapping between host and peripheral
- Dual address cycle supported when the device is the target
- Internal configuration registers accessible from PCI
- Local bus controller (LBC)
 - Multiplexed 32-bit address and data operating at up to 133 MHz
 - Eight chip selects support eight external slaves
 - Up to eight-beat burst transfers
 - 32-, 16-, and 8-bit port sizes are controlled by an on-chip memory controller
 - Three protocol engines available on a per chip select basis:
 - General-purpose chip select machine (GPCM)
 - Three user programmable machines (UPMs)
 - Dedicated single data rate SDRAM controller
 - Parity support
 - Default boot ROM chip select with configurable bus width (8-, 16-, or 32-bit)
- Programmable interrupt controller (PIC)
 - Functional and programming compatibility with the MPC8260 interrupt controller
 - Support for 8 external and 35 internal discrete interrupt sources
 - Support for one external (optional) and seven internal machine checkstop interrupt sources
 - Programmable highest priority request
 - Four groups of interrupts with programmable priority
 - External and internal interrupts directed to communication processor
 - Redirects interrupts to external INTA pin when in core disable mode
 - Unique vector number for each interrupt source
- Dual industry-standard I²C interfaces
 - Two-wire interface





- Multiple master support
- Master or slave I^2C mode support
- On-chip digital filtering rejects spikes on the bus
- System initialization data is optionally loaded from I²C-1 EPROM by boot sequencer embedded hardware
- DMA controller
 - Four independent virtual channels
 - Concurrent execution across multiple channels with programmable bandwidth control
 - All channels accessible by local core and remote PCI masters
 - Misaligned transfer capability
 - Data chaining and direct mode
 - Interrupt on completed segment and chain
 - DMA external handshake signals: DMA_DREQ[0:3]/DMA_DACK[0:3]/DMA_DONE[0:3]. There is one set for each DMA channel. The pins are multiplexed to the parallel IO pins with other QE functions.
- DUART
 - Two 4-wire interfaces (RxD, TxD, RTS, CTS)
 - Programming model compatible with the original 16450 UART and the PC16550D
- System timers
 - Periodic interrupt timer
 - Real-time clock
 - Software watchdog timer
 - Eight general-purpose timers
- IEEE Std. 1149.1TM-compliant, JTAG boundary scan
- Integrated PCI bus and SDRAM clock generation

2 Electrical Characteristics

This section provides the AC and DC electrical specifications and thermal characteristics for the MPC8358E. The device is currently targeted to these specifications. Some of these specifications are independent of the I/O cell, but are included for a more complete reference. These are not purely I/O buffer design specifications.



Electrical Characteristics

2.1 **Overall DC Electrical Characteristics**

This section covers the ratings, conditions, and other characteristics.

2.1.1 Absolute Maximum Ratings

Table 1 provides the absolute maximum ratings.

Table 1. Absolute Maximum Ratings¹

	Characteristic	Symbol	Max Value	Unit	Notes
Core supply voltage		V_{DD}	-0.3 to 1.32	V	—
PLL supply voltage		AV _{DD}	-0.3 to 1.32	V	—
DDR and DDR2 DR	AM I/O voltage DDR DDR2	GV _{DD}	-0.3 to 2.75 -0.3 to 1.89	V	
Three-speed Etherne	et I/O, MII management voltage	LV _{DD}	-0.3 to 3.63	V -	
PCI, local bus, DUAF SPI, and JTAG I/O ve	RT , system control and power management, I^2C , oltage	OV _{DD}	-0.3 to 3.63	V	_
Input voltage	DDR DRAM signals	MV _{IN}	-0.3 to (GV _{DD} + 0.3)	V	2, 5
	DDR DRAM reference	MV _{REF}	-0.3 to (GV _{DD} + 0.3)	V	2, 5
	Three-speed Ethernet signals	LV _{IN}	-0.3 to (LV _{DD} + 0.3)	V	4, 5
	Local bus, DUART, CLKIN, system control and power management, I ² C, SPI, and JTAG signals	OV _{IN}	-0.3 to (OV _{DD} + 0.3)	V	3, 5
	PCI	OV _{IN}	-0.3 to (OV _{DD} + 0.3)	V	6
Storage temperature	range	T _{STG}	-55 to 150	°C	—

Notes:

- 1. Functional and tested operating conditions are given in Table 2. Absolute maximum ratings are stress ratings only, and functional operation at the maximums is not guaranteed. Stresses beyond those listed may affect device reliability or cause permanent damage to the device.
- Caution: MV_{IN} must not exceed GV_{DD} by more than 0.3 V. This limit may be exceeded for a maximum of 100 ms during power-on reset and power-down sequences.
- 3. Caution: OV_{IN} must not exceed OV_{DD} by more than 0.3 V. This limit may be exceeded for a maximum of 100 ms during power-on reset and power-down sequences.
- 4. **Caution:** LV_{IN} must not exceed LV_{DD} by more than 0.3 V. This limit may be exceeded for a maximum of 100 ms during power-on reset and power-down sequences.
- 5. $(M,L,O)V_{IN}$ and MV_{REF} may overshoot/undershoot to a voltage and for a maximum duration as shown in Figure 2.
- 6. OV_{IN} on the PCI interface may overshoot/undershoot according to the PCI Electrical Specification for 3.3-V operation, as shown in Figure 3.



Clock Input Timing

4.1 DC Electrical Characteristics

Table 6 provides the clock input (CLKIN/PCI_SYNC_IN) DC timing specifications for the device.

Parameter	Condition	Symbol	Min	Мах	Unit
Input high voltage	_	V _{IH}	2.7	OV _{DD} + 0.3	V
Input low voltage	_	V _{IL}	-0.3	0.4	V
CLKIN input current	$0 V \le V_{IN} \le OV_{DD}$	I _{IN}	—	±10	μA
PCI_SYNC_IN input current	$\begin{array}{c} 0 \ V \leq V_{IN} \leq 0.5V \ or \\ OV_{DD} - 0.5V \leq V_{IN} \leq OV_{DD} \end{array} \end{array} \label{eq:eq:overlap}$	I _{IN}	_	±10	μA
PCI_SYNC_IN input current	$0.5~V \leq V_{IN} \leq OV_{DD} - 0.5~V$	I _{IN}	—	±100	μA

 Table 6. CLKIN DC Electrical Characteristics

4.2 AC Electrical Characteristics

The primary clock source for the device can be one of two inputs, CLKIN or PCI_CLK, depending on whether the device is configured in PCI host or PCI agent mode. Table 7 provides the clock input (CLKIN/PCI_CLK) AC timing specifications for the device.

Parameter/Condition	Symbol	Min	Typical	Мах	Unit	Notes
CLKIN/PCI_CLK frequency	f _{CLKIN}	—	—	66.67	MHz	1
CLKIN/PCI_CLK cycle time	t _{CLKIN}	15	—	—	ns	_
CLKIN/PCI_CLK rise and fall time	t _{KH} , t _{KL}	0.6	1.0	2.3	ns	2
CLKIN/PCI_CLK duty cycle	t _{KHK} /t _{CLKIN}	40	—	60	%	3
CLKIN/PCI_CLK jitter	—	—	—	±150	ps	4, 5

Table 7. CLKIN AC Timing Specifications

Notes:

1. Caution: The system, core, USB, security, and 10/100/1000 Ethernet must not exceed their respective maximum or minimum operating frequencies.

- 2. Rise and fall times for CLKIN/PCI_CLK are measured at 0.4 V and 2.7 V.
- 3. Timing is guaranteed by design and characterization.
- 4. This represents the total input jitter—short term and long term—and is guaranteed by design.
- 5. The CLKIN/PCI_CLK driver's closed loop jitter bandwidth should be <500 kHz at -20 dB. The bandwidth must be set low to allow cascade-connected PLL-based devices to track CLKIN drivers with the specified jitter.



Interface	Interface Operating Frequency (MHz)	Max Interface Bit Rate (Mbps)	Min QUICC Engine Operating Frequency ¹ (MHz)	Notes
UART/async HDLC	3.68 (max internal ref clock)	115 (Kbps)	20	—
BISYNC	2 (max)	2	20	_
USB	48 (ref clock)	12	96	—

Table 12. QUICC Engine Block Operating Frequency Limitations (continued)

Notes:

1. The QUICC Engine module needs to run at a frequency higher than or equal to what is listed in this table.

2. 'F' is the actual interface operating frequency.

3. The bit rate limit is independent of the data bus width (that is, the same for serial, nibble, or octal interfaces).

4. TDM in high-speed mode for serial data interface.

6 DDR and DDR2 SDRAM

This section describes the DC and AC electrical specifications for the DDR and DDR2 SDRAM interface of the MPC8358E.

6.1 DDR and DDR2 SDRAM DC Electrical Characteristics

Table 13 provides the recommended operating conditions for the DDR2 SDRAM component(s) of the device when $GV_{DD}(typ) = 1.8 \text{ V}$.

Parameter/Condition	Symbol	Min	Мах	Unit	Notes
I/O supply voltage	GV _{DD}	1.71	1.89	V	1
I/O reference voltage	MV _{REF}	$0.49 imes GV_{DD}$	$0.51 imes GV_{DD}$	V	2
I/O termination voltage	V _{TT}	MV _{REF} – 0.04	MV _{REF} + 0.04	V	3
Input high voltage	V _{IH}	MV _{REF} + 0.125	GV _{DD} + 0.3	V	—
Input low voltage	V _{IL}	-0.3	MV _{REF} – 0.125	V	—
Output leakage current	I _{OZ}	—	±10	μA	4
Output high current (V _{OUT} = 1.420 V)	I _{ОН}	-13.4	_	mA	—
Output low current (V _{OUT} = 0.280 V)	I _{OL}	13.4	_	mA	—
MV _{REF} input leakage current	I _{VREF}	—	±10	μA	—

Table 13. DDR2 SDRAM DC Electrical Characteristics for GV_{DD}(typ) = 1.8 V



DDR and DDR2 SDRAM

Figure 7 provides the AC test load for the DDR bus.

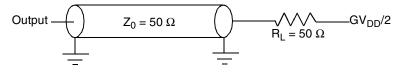


Figure 7. DDR AC Test Load

Table 21. DDR and DDR2 SDRAM Measurement Conditions

Symbol	DDR	DDR2	Unit	Notes
V _{TH}	MV _{REF} ± 0.31 V	MV _{REF} ± 0.25 V	V	1
V _{OUT}	$0.5 imes GV_{DD}$	$0.5 imes GV_{DD}$	V	2

Notes:

1. Data input threshold measurement point.

2. Data output measurement point.

Figure 8 shows the DDR SDRAM output timing diagram for source synchronous mode.

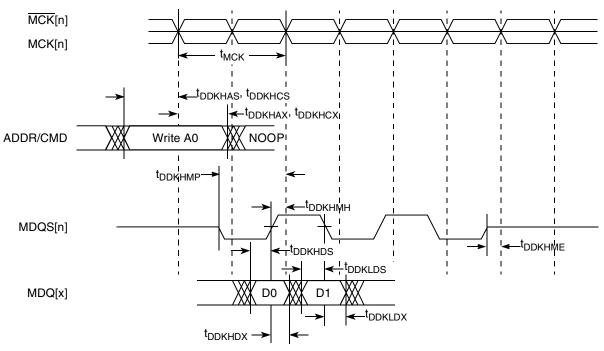


Figure 8. DDR SDRAM Output Timing Diagram for Source Synchronous Mode



UCC Ethernet Controller: Three-Speed Ethernet, MII Management

Figure 11 shows the MII transmit AC timing diagram.

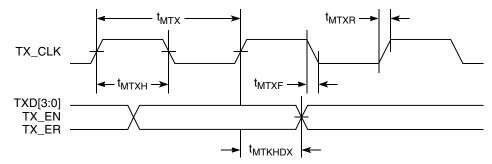


Figure 11. MII Transmit AC Timing Diagram

8.2.2.2 MII Receive AC Timing Specifications

Table 29 provides the MII receive AC timing specifications.

Table 29. MII Receive AC Timing Specifications

At recommended operating conditions with LV_{DD}/OV_{DD} of 3.3 V ± 10%.

Parameter/Condition	Symbol ¹	Min	Тур	Мах	Unit
RX_CLK clock period 10 Mbps	t _{MRX}	_	400	—	ns
RX_CLK clock period 100 Mbps	t _{MRX}	_	40	—	ns
RX_CLK duty cycle	t _{MRXH} /t _{MRX}	35	_	65	%
RXD[3:0], RX_DV, RX_ER setup time to RX_CLK	t _{MRDVKH}	10.0	_	—	ns
RXD[3:0], RX_DV, RX_ER hold time to RX_CLK	t _{MRDXKH}	10.0	_	—	ns
RX_CLK clock rise time, (20% to 80%)	t _{MRXR}	1.0	_	4.0	ns
RX_CLK clock fall time, (80% to 20%)	t _{MRXF}	1.0	_	4.0	ns

Note:

1. The symbols used for timing specifications follow the pattern of t_{(first two letters of functional block)(signal)(state)(reference)(state) for inputs and t_{(first two letters of functional block)(reference)(state)(signal)(state)} for outputs. For example, t_{MRDVKH} symbolizes MII receive timing (MR) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{MRX} clock reference (K) going to the high (H) state or setup time. Also, t_{MRDXKL} symbolizes MII receive timing (GR) with respect to the time data input signals (D) went invalid (X) relative to the t_{MRX} clock reference (K) going to the low (L) state or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{MRX} represents the MII (M) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).}

Figure 12 provides the AC test load.

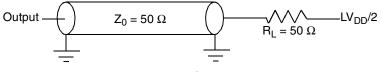


Figure 12. AC Test Load



JTAG

10.2 JTAG AC Electrical Characteristics

This section describes the AC electrical specifications for the IEEE 1149.1 (JTAG) interface of the device.

Table 42 provides the JTAG AC timing specifications as defined in Figure 29 through Figure 32.

Table 42. JTAG AC Timing Specifications (Independent of CLKIN)¹

At recommended operating conditions (see Table 2).

Parameter	Symbol ²	Min	Мах	Unit	Notes
JTAG external clock frequency of operation	f _{JTG}	0	33.3	MHz	—
JTAG external clock cycle time	t _{JTG}	30	_	ns	—
JTAG external clock duty cycle	t _{JTKHKL} /t _{JTG}	45	55	%	—
JTAG external clock rise and fall times	t _{JTGR} & t _{JTGF}	0	2	ns	_
TRST assert time	t _{TRST}	25	_	ns	3
Input setup times: Boundary-scan data TMS, TDI	t _{JTDVKH} t _{JTIVKH}	4 4		ns	4
Input hold times: Boundary-scan data TMS, TDI	t _{JTDXKH} t _{JTIXKH}	10 10		ns	4
Valid times: Boundary-scan data TDO	t _{JTKLDV} t _{JTKLOV}	2 2	11 11	ns	5
Output hold times: Boundary-scan data TDO	t _{jtkldx} t _{jtklox}	2 2		ns	5
JTAG external clock to output high impedance: Boundary-scan data TDO	t _{jtkldz} t _{jtkloz}	2 2	19 9	ns	5, 6 6

Notes:

- 2. The symbols used for timing specifications herein follow the pattern of t_{(first two letters of functional block)(signal)(state) (reference)(state) for inputs and t_{(first two letters of functional block)(reference)(state)(signal)(state)} for outputs. For example, t_{JTDVKH} symbolizes JTAG device timing (JT) with respect to the time data input signals (D) reaching the valid state (V) relative to the t_{JTG} clock reference (K) going to the high (H) state or setup time. Also, t_{JTDXKH} symbolizes JTAG timing (JT) with respect to the time data input signals (D) went invalid (X) relative to the t_{JTG} clock reference (K) going to the high (H) state. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).}
- 3. TRST is an asynchronous level sensitive signal. The setup time is for test purposes only.
- 4. Non-JTAG signal input timing with respect to t_{TCLK} .
- 5. Non-JTAG signal output timing with respect to $\ensuremath{t_{\text{TCLK}}}$.
- 6. Guaranteed by design and characterization.

^{1.} All outputs are measured from the midpoint voltage of the falling/rising edge of t_{TCLK} to the midpoint of the signal in question. The output timings are measured at the pins. All output timings assume a purely resistive 50- Ω load (see Figure 21). Time-of-flight delays must be added for trace lengths, vias, and connectors in the system.



12 PCI

This section describes the DC and AC electrical specifications for the PCI bus of the MPC8358E.

12.1 PCI DC Electrical Characteristics

Table 45 provides the DC electrical characteristics for the PCI interface of the device.

Parameter	Symbol	Test Condition	Min	Мах	Unit
High-level input voltage	V _{IH}	$V_{OUT} \ge V_{OH}$ (min) or	$0.5 imes OV_{DD}$	OV _{DD} + 0.5	V
Low-level input voltage	V _{IL}	$V_{OUT} \le V_{OL}$ (max)	-0.5	$0.3 imes OV_{DD}$	V
High-level output voltage	V _{OH}	I _{OH} = -500 μA	$0.9 imes OV_{DD}$		V
Low-level output voltage	V _{OL}	l _{OL} = 1500 μA		$0.1 imes OV_{DD}$	V
Input current	I _{IN}	$0 \text{ V} \leq {V_{IN}}^1 \leq OV_{DD}$	_	±10	μA

Table 45. PCI DC Electrical Characteristics

Note:

1. Note that the symbol V_{IN} , in this case, represents the OV_{IN} symbol referenced in Table 1 and Table 2.

12.2 PCI AC Electrical Specifications

This section describes the general AC timing parameters of the PCI bus of the device. Note that the PCI_CLK or PCI_SYNC_IN signal is used as the PCI input clock depending on whether the device is configured as a host or agent device. Table 46 provides the PCI AC timing specifications at 66 MHz.

Parameter	Symbol ¹	Min	Мах	Unit	Notes
Clock to output valid	t _{PCKHOV}	—	6.0	ns	2
Output hold from clock	t _{PCKHOX}	1	_	ns	2
Clock to output high impedance	t _{PCKHOZ}	—	14	ns	2, 3
Input setup to clock	t _{PCIVKH}	3.0	_	ns	2, 4
Input hold from clock	t _{PCIXKH}	0.3	_	ns	2, 4

Notes:

The symbols used for timing specifications follow the pattern of t<sub>(first two letters of functional block)(signal)(state)(reference)(state) for inputs and t_{(first two letters of functional block)(reference)(state)(signal)(state)} for outputs. For example, t_{PCIVKH} symbolizes PCI timing (PC) with respect to the time the input signals (I) reach the valid state (V) relative to the PCI_SYNC_IN clock, t_{SYS}, reference (K) going to the high (H) state or setup time. Also, t_{PCRHFV} symbolizes PCI timing (PC) with respect to the time hard reset (R) went high (H) relative to the frame signal (F) going to the valid (V) state.
</sub>

2. See the timing measurement conditions in the PCI 2.2 Local Bus Specifications.

3. For purposes of active/float timing measurements, the Hi-Z or off-state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.

4. Input timings are measured at the pin.

Figure 37 shows the PCI output AC timing conditions.

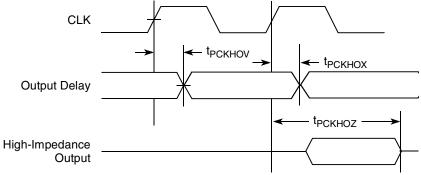


Figure 37. PCI Output AC Timing Measurement Condition

13 Timers

This section describes the DC and AC electrical specifications for the timers of the MPC8358E.

13.1 Timers DC Electrical Characteristics

Table 48 provides the DC electrical characteristics for the device timer pins, including TIN, TOUT, TGATE, and RTC_CLK.

Characteristic	Symbol	Condition	Min	Мах	Unit
Output high voltage	V _{OH}	I _{OH} = -6.0 mA	2.4	—	V
Output low voltage	V _{OL}	I _{OL} = 6.0 mA	_	0.5	V
Output low voltage	V _{OL}	I _{OL} = 3.2 mA	_	0.4	V
Input high voltage	V _{IH}	—	2.0	OV _{DD} + 0.3	V
Input low voltage	V _{IL}	—	-0.3	0.8	V
Input current	I _{IN}	$0 \ V \leq V_{IN} \leq OV_{DD}$	_	±10	μA

Table 48. Timers DC Electrical Characteristics

13.2 Timers AC Timing Specifications

Table 49 provides the timer input and output AC timing specifications.

Table 49. Timers Input AC Timing Specifications¹

Characteristic	Symbol ²	Тур	Unit
Timers inputs—minimum pulse width	t _{TIWID}	20	ns

Notes:

1. Input specifications are measured from the 50% level of the signal to the 50% level of the rising edge of CLKIN. Timings are measured at the pin.

2. Timers inputs and outputs are asynchronous to any visible clock. Timers outputs should be synchronized before use by any external synchronous logic. Timers inputs are required to be valid for at least t_{TIWID} ns to ensure proper operation.



TDM/SI

Table 56. TDM/SI DC Electrical Characteristics (continued)

Characteristic	Symbol	Condition	Min	Мах	Unit
Input low voltage	V _{IL}	—	-0.3	0.8	V
Input current	I _{IN}	$0 \ V \le V_{IN} \le OV_{DD}$	_	±10	μA

17.2 TDM/SI AC Timing Specifications

Table 57 provides the TDM/SI input and output AC timing specifications.

Table 57. TDM/SI AC Timing Specifications¹

Characteristic	Symbol ²	Min	Max ³	Unit
TDM/SI outputs—External clock delay	t _{SEKHOV}	2	10	ns
TDM/SI outputs—External clock high impedance	t _{SEKHOX}	2	10	ns
TDM/SI inputs—External clock input setup time	t _{SEIVKH}	5	-	ns
TDM/SI inputs—External clock input hold time	t _{SEIXKH}	2		ns

Notes:

1. Output specifications are measured from the 50% level of the rising edge of CLKIN to the 50% level of the signal. Timings are measured at the pin.

- 2. The symbols used for timing specifications follow the pattern of t_{(first two letters of functional block)(signal)(state)(reference)(state) for inputs and t_{(first two letters of functional block)(reference)(state)(signal)(state) for outputs. For example, t_{SEKHOX} symbolizes the TDM/SI outputs external timing (SE) for the time t_{TDM/SI} memory clock reference (K) goes from the high state (H) until outputs (O) are invalid (X).}}
- 3. Timings are measured from the positive or negative edge of the clock, according to SIxMR [CE] and SITXCEI[TXCEIx]. See the MPC8360E Integrated Communications Processor Family Reference Manual for more details.

Figure 43 provides the AC test load for the TDM/SI.

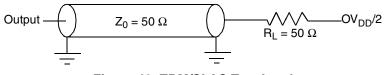


Figure 43. TDM/SI AC Test Load

Figure 44 represents the AC timing from Table 55. Note that although the specifications generally reference the rising edge of the clock, these AC timing diagrams also apply when the falling edge is the active edge.



Package and Pin Listings

21.2 Mechanical Dimensions of the PBGA Package

Figure 52 depicts the mechanical dimensions and bottom surface nomenclature of the 668-PBGA package.

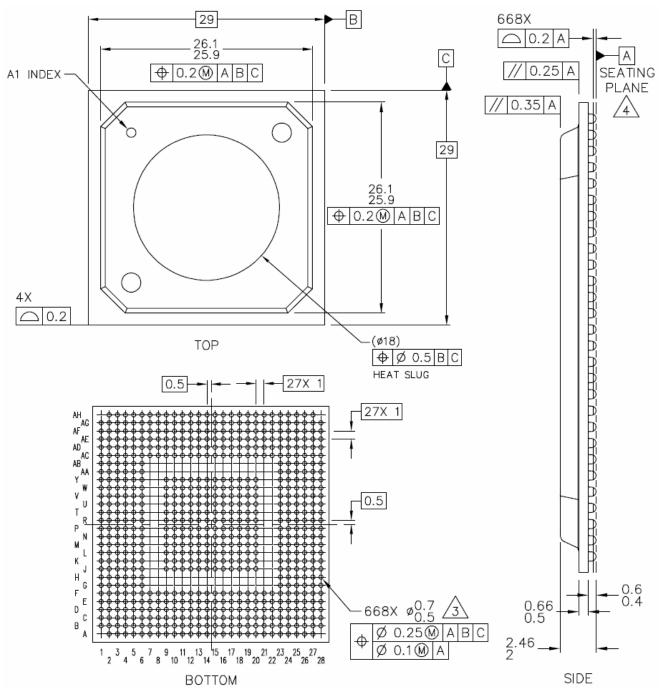


Figure 52. Mechanical Dimensions and Bottom Surface Nomenclature of the PBGA Package

Notes:

- 1. All dimensions are in millimeters.
- 2. Dimensions and tolerances per ASME Y14.5M-1994.
- 3. Maximum solder ball diameter measured parallel to datum A.

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Figure 53 shows the internal distribution of clocks within the MPC8358E.

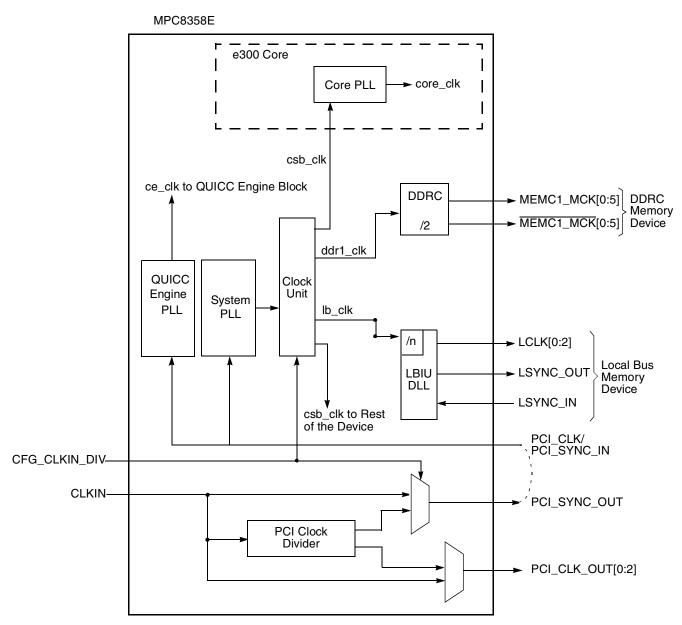


Figure 53. MPC8358E Clock Subsystem

The primary clock source for the device can be one of two inputs, CLKIN or PCI_CLK, depending on whether the device is configured in PCI host or PCI agent mode. Note that in PCI host mode, the primary clock input also depends on whether PCI clock outputs are selected with RCWH[PCICKDRV]. When the device is configured as a PCI host device (RCWH[PCIHOST] = 1) and PCI clock output is selected (RCWH[PCICKDRV] = 1), CLKIN is its primary input clock. CLKIN feeds the PCI clock divider (÷2) and the multiplexors for PCI_SYNC_OUT and PCI_CLK_OUT. The CFG_CLKIN_DIV configuration



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input selects whether CLKIN or CLKIN/2 is driven out on the PCI_SYNC_OUT signal. The OCCR[PCIOEN*n*] parameters enable the PCI_CLK_OUT*n*, respectively.

PCI_SYNC_OUT is connected externally to PCI_SYNC_IN to allow the internal clock subystem to synchronize to the system PCI clocks. PCI_SYNC_OUT must be connected properly to PCI_SYNC_IN, with equal delay to all PCI agent devices in the system, to allow the device to function. When the device is configured as a PCI agent device, PCI_CLK is the primary input clock. When the device is configured as a PCI agent device the CLKIN and the CFG_CLKIN_DIV signals should be tied to GND.

When the device is configured as a PCI host device (RCWH[PCIHOST] = 1) and PCI clock output is disabled (RCWH[PCICKDRV] = 0), clock distribution and balancing done externally on the board. Therefore, PCI_SYNC_IN is the primary input clock.

As shown in Figure 53, the primary clock input (frequency) is multiplied by the QUICC Engine block phase-locked loop (PLL), the system PLL, and the clock unit to create the QUICC Engine clock (ce_clk), the coherent system bus clock (csb_clk), the internal DDRC1 controller clock ($ddr1_clk$), and the internal clock for the local bus interface unit and DDR2 memory controller (lb_clk).

The *csb_clk* frequency is derived from a complex set of factors that can be simplified into the following equation:

 $csb_clk = \{PCI_SYNC_IN \times (1 + CFG_CLKIN_DIV)\} \times SPMF$

In PCI host mode, PCI_SYNC_IN \times (1 + CFG_CLKIN_DIV) is the CLKIN frequency; in PCI agent mode, CFG_CLKIN_DIV must be pulled down (low), so PCI_SYNC_IN \times (1 + CFG_CLKIN_DIV) is the PCI_CLK frequency.

The *csb_clk* serves as the clock input to the e300 core. A second PLL inside the e300 core multiplies up the *csb_clk* frequency to create the internal clock for the e300 core (*core_clk*). The system and core PLL multipliers are selected by the SPMF and COREPLL fields in the reset configuration word low (RCWL) which is loaded at power-on reset or by one of the hard-coded reset options. See Chapter 4, "Reset, Clocking, and Initialization," in the *MPC8360E PowerQUICC II Pro Integrated Communications Processor Family Reference Manual* for more information on the clock subsystem.

The *ce_clk* frequency is determined by the QUICC Engine PLL multiplication factor (RCWL[CEPMF) and the QUICC Engine PLL division factor (RCWL[CEPDF]) according to the following equation:

 $ce_clk = (primary clock input \times CEPMF) \div (1 + CEPDF)$

The internal *ddr1_clk* frequency is determined by the following equation:

 $ddr1_clk = csb_clk \times (1 + RCWL[DDR1CM])$

Note that the lb_clk clock frequency (for DDRC2) is determined by RCWL[LBCM]. The *internal* $ddr1_clk$ frequency is not the external memory bus frequency; $ddr1_clk$ passes through the DDRC1 clock divider (÷2) to create the differential DDRC1 memory bus clock outputs (MEMC1_MCK and MEMC1_MCK). However, the data rate is the same frequency as $ddr1_clk$.

The internal *lb_clk* frequency is determined by the following equation:

 $lb_clk = csb_clk \times (1 + \text{RCWL[LBCM]})$



22.1 System PLL Configuration

The system PLL is controlled by the RCWL[SPMF] and RCWL[SVCOD] parameters. Table 68 shows the multiplication factor encodings for the system PLL.

RCWL[SPMF]	System PLL Multiplication Factor
0000	× 16
0001	Reserved
0010	× 2
0011	× 3
0100	× 4
0101	× 5
0110	× 6
0111	× 7
1000	× 8
1001	× 9
1010	× 10
1011	× 11
1100	× 12
1101	× 13
1110	× 14
1111	× 15

Table 68. System PLL Multiplication Factors

The RCWL[SVCOD] denotes the system PLL VCO internal frequency as shown in Table 69.

Table 69. System PLL VCO Divider

RCWL[SVCOD]	VCO Divider
00	4
01	8
10	2
11	Reserved

NOTE

The VCO divider must be set properly so that the system VCO frequency is in the range of 600–1400 MHz.

NP

The system VCO frequency is derived from the following equations:

- $csb_clk = \{PCI_SYNC_IN \times (1 + CFG_CLKIN_DIV)\} \times SPMF$
- System VCO Frequency = csb_clk × VCO divider (if both RCWL[DDRCM] and RCWL[LBCM] are cleared) OR
- System VCO frequency = 2 × *csb_clk* × VCO divider (if either RCWL[DDRCM] or RCWL[LBCM] are set).

As described in Section 22, "Clocking," the LBCM, DDRCM, and SPMF parameters in the reset configuration word low and the CFG_CLKIN_DIV configuration input signal select the ratio between the primary clock input (CLKIN or PCI_CLK) and the internal coherent system bus clock (*csb_clk*). Table 70 shows the expected frequency values for the CSB frequency for select *csb_clk* to CLKIN/PCI_SYNC_IN ratios.

			Ir	nput Clock Fre	equency (MHz	:) ²
CFG_CLKIN_DIV at Reset ¹	SPMF	<i>csb_clk</i> : Input Clock Ratio ²	16.67	25	33.33	66.67
				<i>csb_clk</i> Freq	uency (MHz)	
Low	0010	2:1				133
Low	0011	3:1			100	200
Low	0100	4:1		100	133	266
Low	0101	5:1		125	166	333
Low	0110	6:1	100	150	200	
Low	0111	7:1	116	175	233	
Low	1000	8:1	133 200		266	
Low	1001	9:1	150 225		300	
Low	1010	10:1	166	250	333	
Low	1011	11:1	183	275		,
Low	1100	12:1	200	300		
Low	1101	13:1	216	325		
Low	1110	14:1	233		1	
Low	1111	15:1	250			
Low	0000	16:1	266			
High	0010	2:1		_		133
High	0011	3:1			100	200
High	0100	4:1	133		266	
High	0101	5:1			166	333

Table 70. CSB Frequency Options

Clocking

			In	put Clock Fr	equency (MHz) ²	
CFG_CLKIN_DIV at Reset ¹	SPMF	<i>csb_clk</i> : Input Clock Ratio ²	16.67	25	33.33	66.67	
					csb_clk Frequency (MHz)		
High	0110	6:1			200		
High	0111	7:1			233		
High	1000	8:1					
High	1001	9:1					
High	1010	10:1					
High	1011	11:1					
High	1100	12:1					
High	1101	13:1					
High	1110	14:1					
High	1111	15:1					
High	0000	16:1					

Table 70. CSB Frequency Options (continued)

¹ CFG_CLKIN_DIV is only used for host mode; CLKIN must be tied low and CFG_CLKIN_DIV must be pulled down (low) in agent mode.

² CLKIN is the input clock in host mode; PCI_CLK is the input clock in agent mode.

22.2 Core PLL Configuration

RCWL[COREPLL] selects the ratio between the internal coherent system bus clock (*csb_clk*) and the e300 core clock (*core_clk*). Table 71 shows the encodings for RCWL[COREPLL]. COREPLL values not listed in Table 71 should be considered reserved.

RC	WL[COREP	LL]	core_clk:csb_clk	VCO divider
0–1	2–5	6	Ratio	
nn	0000	n	PLL bypassed (PLL off, <i>csb_clk</i> clocks core directly)	PLL bypassed (PLL off, <i>csb_clk</i> clocks core directly)
00	0001	0	1:1	÷2
01	0001	0	1:1	÷4
10	0001	0	1:1	÷8
11	0001	0	1:1	÷8
00	0001	1	1.5:1	÷2
01	0001	1	1.5:1	÷4
10	0001	1	1.5:1	÷8

Table 71. e300 Core PLL Configuration

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